## 2.5 / 3.3 V, 200 MHz High Speed Multi-Phase PLL Clock Buffer

## Features

- 2.5 V or 3.3 V operation

■ Split output bank power supplies
■ Output frequency range: 6 MHz to 200 MHz
■ 50 ps typical matched-pair output-output skew
■ 50 ps typical cycle-cycle jitter
■ 49.5 / 50.5\% typical output duty cycle
■ Selectable output drive strength
■ Selectable positive or negative edge synchronization
■ Eight LVTTL outputs driving $50 \Omega$ terminated lines
■ LVCMOS / LVTTL overvoltage tolerant reference input
■ Phase adjustments in $625 / 1250$ ps steps up to $\pm 7.5$ ns
■ $2 \times, 4 \times$ multiply and $(1 / 2) \times$, ( $1 / 4$ ) $\times$ divide ratios

- Spread spectrum compatible

■ Industrial temperature range: $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$

- 32-pin TQFP package


## Description

The CY7B9950 RoboClock ${ }^{\circledR}$ is a low voltage, low power, eight-output, 200 MHz clock driver. It features output phase programmability which is necessary to optimize the clock tree design of high performance computer and communication systems.
The user can program the phase of the output banks through $\mathrm{nF}[0: 1]$ pins. The adjustable phase feature enables the user to skew the outputs to lead or lag the reference clock. Any one of the outputs can be connected to the feedback input to achieve different reference frequency multiplications, divide ratios, and zero input-output delay.
The device also features split output bank power supplies, which enable the user to run two banks (1Qn and 2Qn) at a power supply level different from that of the other two banks (3Qn and 4Qn). Additionally, the three-level PE/HD pin controls the synchronization of the output signals to either the rising or falling edge of the reference clock and selects the drive strength of the output buffers. The high drive option (PE/HD = MID) increases the output current from $\pm 12 \mathrm{~mA}$ to $\pm 24 \mathrm{~mA}(3.3 \mathrm{~V})$.


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## Pinouts

Figure 1. Pin Diagram - 32-Pin TQFP (Top View)


Table 1. Pin Definitions

| Pin | Name | $1 / O^{[1]}$ | Type | Description |
| :---: | :---: | :---: | :---: | :---: |
| 29 | REF | I | LVTTL/LVCMOS | Reference clock input. |
| 13 | FB | I | LVTTL | Feedback input. |
| 27 | TEST | 1 | Three-level | When MID or HIGH, disables PLL ${ }^{[3]}$. REF goes to outputs of Bank 1 and Bank 2. REF also goes to outputs of Bank 3 and Bank 4 through output dividers K and M . Set LOW for normal operation. |
| 22 | sOE\# | I, PD | Two-level | Synchronous output enable. When HIGH, it stops clock outputs (except 2Q0 and 2Q1) in a Low state (for PE = H or M) - 2Q0, and 2Q1 may be used as the feedback signal to maintain phase lock. When test is held at MID level and sOE\# is HIGH, the nF [1:0] pins act as output disable controls for individual banks when nF[1:0] = LL. Set sOE\# Low for normal operation. |
| 4 | PE/HD | I, PU | Three-level | Selects Positive or negative edge control and High or low output drive strength. When Low/High the outputs are synchronized with the negative/positive edge of the reference clock, respectively. When at MID level, the output drive strength is increased and the outputs synchronize with the positive edge of the reference clock (see Table 7 on page 4). |
| $\begin{aligned} & 24,23,26, \\ & 25,1,32,3,2 \end{aligned}$ | nF [1:0] | I | Three-level | Select frequency and phase of the outputs (see Table 2, Table 3, Table 4 on page 4, Table 5 on page 4, and Table 6 on page 4). |
| 31 | FS | I | Three-level | Selects VCO operating frequency range (see Table 5 on page 4) |
| $\begin{aligned} & 19,20,15, \\ & 16,10,11,6 \\ & 7 \end{aligned}$ | nQ[1:0] | 0 | LVTTL | Four banks of two outputs (see Table 2, Table 3, and Table 4 on page 4) |
| 21 | $\mathrm{V}_{\mathrm{DDQ} 1}{ }^{[2]}$ | PWR | Power | Power supply for Bank 1 and Bank 2 output buffers (see Table 8 on page 4 for supply level constraints). |
| 12 | $\mathrm{V}_{\text {DDQ3 }}{ }^{[2]}$ | PWR | Power | Power supply for Bank 3 output buffers (see Table 8 on page 4 for supply level constraints). |
| 5 | $\mathrm{V}_{\text {DDQ4 }}{ }^{[2]}$ | PWR | Power | Power supply for Bank 4 output buffers (see Table 8 on page 4 for supply level constraints). |
| 14,30 | $\mathrm{V}_{\mathrm{D}}{ }^{[2]}$ | PWR | Power | Power supply for internal circuitry (see Table 8 on page 4 for supply level constraints). |
| 8,9,17,18,28 | $\mathrm{V}_{\text {SS }}$ | PWR | Power | Ground |

## Notes

1. PD indicates an internal pull-down and PU indicates an internal pull-up. 3 indicates a three-level input buffer.
2. A bypass capacitor $(0.1 \mu \mathrm{~F})$ must be placed as close as possible to each positive power pin ( $<0.2^{\prime \prime}$ ). If these bypass capacitors are not close to the pins their high-frequency filtering characteristic are cancelled by the lead inductance of the traces.

Table 6. Output Skew Settings

| nF[1:0] | $\begin{gathered} \text { Skew } \\ \text { (1Q[0:1],2Q[0:1]) } \end{gathered}$ | Skew (3Q[0:1]) | Skew (4Q[0:1]) |
| :---: | :---: | :---: | :---: |
| LL ${ }^{[5]}$ | $-4 t_{U}$ | Divide by 2 | Divide by 2 |
| LM | $-3 \mathrm{t}_{\mathrm{U}}$ | $-6 \mathrm{t}_{\mathrm{U}}$ | $-6 \mathrm{t}_{\mathrm{U}}$ |
| LH | $-2 \mathrm{t}_{\mathrm{U}}$ | $-4 t_{U}$ | $-4 \mathrm{t}_{\mathrm{U}}$ |
| ML | $-1 \mathrm{t}_{\mathrm{U}}$ | $-2 \mathrm{t}_{\mathrm{U}}$ | $-2 \mathrm{t}_{\mathrm{U}}$ |
| MM | Zero skew | Zero skew | Zero skew |
| MH | $+1 t_{U}$ | $+2 \mathrm{t}_{\mathrm{U}}$ | $+2 t_{U}$ |
| HL | $+2 t_{U}$ | $+4 t_{U}$ | $+4 t_{U}$ |
| HM | $+3 \mathrm{t}_{\mathrm{U}}$ | $+6 \mathrm{t}_{\mathrm{U}}$ | $+6 \mathrm{t}_{\mathrm{U}}$ |
| HH | $+4 \mathrm{t}_{U}$ | Divide by 4 | Inverted ${ }^{[6]}$ |

In addition to determining whether the outputs synchronize to the rising or the falling edge of the reference signal, the 3-level PE/HD pin controls the output buffer drive strength as indicated in Table 7.
The RoboClock ${ }^{\circledR}$ CY7B9950 features split power supply buses for Banks 1 and 2, Bank 3 and Bank 4, which enables the user to obtain both 3.3 V and 2.5 V output signals from one device. The core power supply (VDD) must be set at a level that is equal to or higher than any one of the output power supplies.

Table 7. PE/HD Settings

| PE/HD | Synchronization | Output drive strength ${ }^{[7]}$ |
| :---: | :---: | :---: |
| L | Negative | Low drive |
| M | Positive | High drive |
| H | Positive | Low drive |

Table 8. Power Supply Constraints

| $\mathbf{V}_{\mathbf{D D}}$ | $\mathbf{V}_{\mathbf{D D Q 1}{ }^{[8]}} \mathbf{V}_{\mathbf{D D Q 3}}{ }^{[8]}$ | $\mathbf{V}_{\mathbf{D D Q 4}}{ }^{[8]}$ |  |
| :---: | :---: | :---: | :---: |
| 3.3 V | 3.3 V or 2.5 V | 3.3 V or 2.5 V | 3.3 V or 2.5 V |
| 2.5 V | 2.5 V | 2.5 V | 2.5 V |

## Governing Agencies

The following agencies provide specifications that apply to the RoboClock ${ }^{\circledR}$ CY7B9950. The agency name and relevant specification is listed below.

Table 9. Governing Agencies and Specifications

| Agency name | Specification |
| :---: | :--- |
| JEDEC | JESD 51 (theta JA), JESD 65 (skew, jitter) |
| IEEE | 1596.3 (jitter specs) |
| UL-194_V0 | 94 (moisture grading) |
| MIL | 883E method 1012.1 (therma theta JC) |

## Notes

3. When TEST $=$ MID and $s O E \#=H I G H, ~ P L L$ remains active with $n F[1: 0]=$ LL functioning as an output disable control for individual output banks. Skew selections remain in effect unless nF[1:0] = LL.
4. These states are used to program the phase of the respective banks (see Table 6 on page 4).
5. LL disables outputs if TEST $=$ MID and $s O E \#=\mathrm{HIGH}$.
6. When $4 \mathrm{Q}[0: 1]$ are set to run inverted (HH mode), sOE\# disables these outputs HIGH when PE/HD $=$ HIGH or MID and sOE\# disables them LOW when PE/HD = LOW
7. Please refer to "DC Parameters" section for $\mathrm{I}_{\mathrm{OH}} / \mathrm{l}_{\mathrm{OL}}$ specifications.
8. $\mathrm{V}_{\mathrm{DDQ} 1 / 3 / 4}$ must not be set at a level higher than that of $\mathrm{V}_{\mathrm{DD}}$. They can be set at different levels from each other, e.g., $\mathrm{V}_{\mathrm{DD}}=3.3 \mathrm{~V}, \mathrm{~V}_{\mathrm{DDQ}}=3.3 \mathrm{~V}, \mathrm{~V}_{\mathrm{DDQ}}=2.5 \mathrm{~V}$ and $\mathrm{V}_{\text {DDQ4 }}=2.5 \mathrm{~V}$.

## Absolute Maximum Conditions

| Parameter | Description | Condition | Min | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {D }}$ | Supply voltage |  | - | 4.6 | V |
| $\mathrm{V}_{\text {IN(MIN }}$ | Input voltage | Relative to $\mathrm{V}_{S S}$ | $\mathrm{V}_{\mathrm{SS}}-0.3$ | - | V |
| $\mathrm{V}_{\text {IN(MAX) }}$ | Input voltage | Relative to $\mathrm{V}_{\mathrm{DD}}$ | - | $\mathrm{V}_{\mathrm{DD}}+0.3$ | V |
| $\mathrm{T}_{\text {S }}$ | Temperature, storage | Non-functional | -65 | 150 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{J}$ | Temperature, junction | Functional | - | 155 | ${ }^{\circ} \mathrm{C}$ |
| $\varnothing_{\text {JC }}$ | Dissipation, junction to case | Mil-Spec 883E Method 1012.1 | - | 42 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| $\varnothing_{\text {JA }}$ | Dissipation, junction to ambient | JEDEC (JESD 51) | - | 105 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| ESD ${ }_{\text {HBM }}$ | ESD protection (human body model) | MIL-STD-883, Method 3015 | 2000 | - | V |
| UL-94 | Flammability rating | At 1/8 in. | V-0 |  |  |
| MSL | Moisture sensitivity level |  | 1 |  |  |
| FIT | Failure in time | Manufacturing testing | 10 |  | ppm |

## Operating Conditions

| Parameter | Description | Condition | Min | Max | Unit |
| :--- | :--- | :--- | :---: | :---: | :---: |
| $\mathrm{V}_{\mathrm{DD}}$ | Operating voltage | $2.5 \mathrm{~V} \pm 5 \%$ | 2.375 | 2.625 | V |
|  |  | $3.3 \mathrm{~V} \pm 10 \%$ | 2.97 | 3.63 | V |
| $\mathrm{~T}_{\mathrm{A}}$ | Temperature, operating ambient |  | -40 | 85 | ${ }^{\circ} \mathrm{C}$ |

## DC Electrical Specifications at 2.5 V

| Parameter | Description |  | dition | Min | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {IL }}$ | Input low voltage | REF, FB and sOE\# Inputs |  | - | 0.7 | V |
| $\mathrm{V}_{\mathrm{IH}}$ | Input high voltage |  |  | 1.7 | - | V |
| $\mathrm{V}_{\mathrm{IHH}}{ }^{[9]}$ | Input high voltage | 3-level inputs (TEST, FS, nF[1:0], PE/HD) (These pins are normally wired to $\mathrm{V}_{\mathrm{DD}}$, GND, or unconnected.) |  | $\mathrm{V}_{\mathrm{DD}}-0.4$ | - | V |
| $\mathrm{V}_{\mathrm{IMM}}{ }^{[9]}$ | Input MID voltage |  |  | $\mathrm{V}_{\mathrm{DD}} / 2-0.2$ | $\mathrm{V}_{\mathrm{DD}} / 2+0.2$ | V |
| $\mathrm{V}_{\text {ILL }}{ }^{\text {9] }}$ | Input low voltage |  |  | - | 0.4 | V |
| $\mathrm{I}_{\text {IL }}$ | Input leakage current | $\begin{aligned} & \mathrm{V}_{I N}=\mathrm{V}_{\mathrm{DD}} / G N D, \\ & \left.\mathrm{~V}_{\mathrm{DD}}=\max . \text { (REF and } \mathrm{FB} \text { inputs }\right) \end{aligned}$ |  | -5 | 5 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{3}$ | 3-level input DC current | HIGH, $\mathrm{V}_{\text {IN }}=\mathrm{V}_{\text {DD }}$ | 3-level inputs (TEST, FS, nF[1:0], PE/HD) | - | 200 | $\mu \mathrm{A}$ |
|  |  | MID, $\mathrm{V}_{\text {IN }}=\mathrm{V}_{\mathrm{DD}} / 2$ |  | -50 | 50 | $\mu \mathrm{A}$ |
|  |  | LOW, $\mathrm{V}_{\text {IN }}=\mathrm{V}_{\text {SS }}$ |  | -200 | - | $\mu \mathrm{A}$ |
| IPU | Input pull-up current | $\mathrm{V}_{\mathrm{IN}}=\mathrm{V}_{\text {SS }}, \mathrm{V}_{\mathrm{DD}}=$ max. |  | -25 | - | $\mu \mathrm{A}$ |
| IPD | Input pull-down current | $\mathrm{V}_{\text {IN }}=\mathrm{V}_{\mathrm{DD}}, \mathrm{V}_{\mathrm{DD}}=$ max., (sOE\#) |  | - | 100 | $\mu \mathrm{A}$ |
| $\mathrm{V}_{\mathrm{OL}}$ | Output low voltage | $\mathrm{I}_{\mathrm{OL}}=12 \mathrm{~mA}(\mathrm{PE} / \mathrm{HD}=\mathrm{L} / \mathrm{H}),(\mathrm{nQ}[0: 1])$ |  | - | 0.4 | V |
|  |  | $\mathrm{l}_{\mathrm{OL}}=20 \mathrm{~mA}(\mathrm{PE} / \mathrm{HD}=\mathrm{MID}),(\mathrm{nQ}[0: 1])$ |  | - | 0.4 | V |
| $\mathrm{V}_{\mathrm{OH}}$ | Output high voltage | $\mathrm{I}_{\mathrm{OH}}=-12 \mathrm{~mA}(\mathrm{PE} / \mathrm{HD}=\mathrm{L} / \mathrm{H}),(\mathrm{nQ}[0: 1])$ |  | 2.0 | - | V |
|  |  | $\mathrm{I}_{\mathrm{OH}}=-20 \mathrm{~mA}$ (PE/HD $\left.=\mathrm{MID}\right),(\mathrm{nQ}[0: 1])$ |  | 2.0 | - | V |
| ${ }^{\text {I DDQ }}$ | Quiescent supply current | $\mathrm{V}_{\mathrm{DD}}=$ max., TEST = MID, REF = LOW, sOE\# = LOW, outputs not loaded |  | - | 2 | mA |
| IDD | Dynamic supply current | At 100 MHz |  | 150 |  | mA |
| $\mathrm{C}_{\text {IN }}$ | Input pin capacitance |  |  | 4 |  | pF |

## DC Electrical Specifications at 3.3 V

| Parameter | Description |  | dition | Min | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| VIL | Input LOW voltage | REF, FB and sOE\# Inputs |  | - | 0.8 | V |
| $\mathrm{V}_{\mathrm{IH}}$ | Input HIGH voltage |  |  | 2.0 | - | V |
| $\mathrm{V}_{\mathrm{IHH}}{ }^{[9]}$ | Input HIGH voltage | 3-level inputs (TEST, FS, nF[1:0], PE/HD) (These pins are normally wired to $\mathrm{V}_{\mathrm{DD}}$, GND or unconected.) |  | $\mathrm{V}_{\mathrm{DD}}-0.6$ | - | V |
| $\mathrm{V}_{\mathrm{IMM}}{ }^{[9]}$ | Input MID voltage |  |  | $\mathrm{V}_{\mathrm{DD}} / 2-0.3$ | $\begin{gathered} \mathrm{V}_{\mathrm{DD}} / 2+ \\ 0.3 \end{gathered}$ | V |
| $\mathrm{V}_{\mathrm{ILL}}{ }^{\text {[9] }}$ | Input LOW voltage |  |  | - | 0.6 | V |
| $\mathrm{I}_{\text {IL }}$ | Input leakage current | $\mathrm{V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{DD}} / \mathrm{G}_{\mathrm{ND}}, \mathrm{V}_{\mathrm{DD}}=\max .($ REF and FB inputs) |  | -5 | 5 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{3}$ | 3-level input DC current | HIGH, $\mathrm{V}_{\text {IN }}=\mathrm{V}_{\mathrm{DD}}$ 3-level inputs <br> MID, $\mathrm{V}_{I N}=\mathrm{V}_{\mathrm{DD}} / 2$ (TEST, FS, $n F[1: 0]$, <br> DSS[1:0], PD\#/DIV,  <br> LOW, $\mathrm{V}_{\text {IN }}=\mathrm{V}_{S S}$ PE/HD) | 3-level inputs (TEST, FS, nF[1:0], DS[1:0], PD\#/DIV, PE/HD) | - | 200 | $\mu \mathrm{A}$ |
|  |  |  |  | -50 | 50 | $\mu \mathrm{A}$ |
|  |  |  |  | -200 | - | $\mu \mathrm{A}$ |
| IPU | Input pull-up current | $\mathrm{V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{SS}}, \mathrm{V}_{\mathrm{DD}}=\max$. |  | -100 | - | $\mu \mathrm{A}$ |
| IPD | Input pull-down current | $\mathrm{V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{DD}}, \mathrm{V}_{\mathrm{DD}}=$ max., (sOE\#) |  | - | 100 | $\mu \mathrm{A}$ |
| $\mathrm{V}_{\mathrm{OL}}$ | Output LOW voltage | $\mathrm{I}_{\mathrm{OL}}=12 \mathrm{~mA}(\mathrm{PE} / \mathrm{HD}=\mathrm{L} / \mathrm{H}),(\mathrm{nQ}[0: 1])$ |  | - | 0.4 | V |
|  |  | $\mathrm{I}_{\mathrm{OL}}=24 \mathrm{~mA}(\mathrm{PE} / \mathrm{HD}=\mathrm{MID}),(\mathrm{nQ}[0: 1])$ |  | - | 0.4 | V |
| $\mathrm{V}_{\mathrm{OH}}$ | Output HIGH voltage | $\mathrm{I}_{\mathrm{OH}}=-12 \mathrm{~mA}(\mathrm{PE} / \mathrm{HD}=\mathrm{L} / \mathrm{H}),(\mathrm{nQ}[0: 1])$ |  | 2.4 | - | V |
|  |  | $\mathrm{I}_{\mathrm{OH}}=-24 \mathrm{~mA}(\mathrm{PE} / \mathrm{HD}=\mathrm{MID}),(\mathrm{nQ}[0: 1])$ |  | 2.4 | - | V |
| ${ }^{\text {I DDQ }}$ | Quiescent supply current | $\mathrm{V}_{\mathrm{DD}}=$ max., TEST = MID, REF = LOW, sOE\# = LOW, outputs not loaded |  | - | 2 | mA |
| $\mathrm{IDD}^{\text {D }}$ | Dynamic supply current | At 100 MHz |  | 230 |  | mA |
| $\mathrm{C}_{\text {IN }}$ | Input pin capacitance |  |  | 4 |  | pF |

AC Test Loads and Waveforms
Figure 2. AC Test Loads


## For Lock Output

For All Other Outputs
Figure 3. Output Waveforms

3.3V LVTTL OUTPUT WAVEFORM

2.5V LVTTL OUTPUT WAVEFORM

Note
9. These inputs are normally wired to $\mathrm{V}_{\mathrm{DD}}$, GND or unconnected. Internal termination resistors bias unconnected inputs to $\mathrm{V}_{\mathrm{DD}} / 2$.

Figure 4. Test Waveforms


## AC Input Specifications

| Parameter | Description | Condition | Min | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{T}_{\mathrm{R}}, \mathrm{T}_{\mathrm{F}}$ | Input rise/fall time | 0.8V-2.0 V | - | 10 | ns/V |
| $\mathrm{T}_{\text {PWC }}$ | Input clock pulse | HIGH or LOW | 2 | - | ns |
| $\mathrm{T}_{\text {DCIN }}$ | Input duty cycle |  | 10 | 90 | \% |
| $\mathrm{F}_{\text {REF }}$ | Reference input frequency | FS = LOW | 6 | 50 | MHz |
|  |  | FS = MID | 12 | 100 |  |
|  |  | FS $=\mathrm{HIGH}$ | 24 | 200 |  |

## Switching Characteristics

| Parameter | Description | Condition | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{F}_{\text {OR }}$ | Output frequency range |  | 6 | - | 200 | MHz |
| $\mathrm{VCO}_{\text {LR }}$ | VCO lock range |  | 200 | - | 400 | MHz |
| $\mathrm{VCO}_{\text {LBW }}$ | VCO loop bandwidth |  | 0.25 | - | 3.5 | MHz |
| $\mathrm{t}_{\text {SKEWPR }}$ | Matched-pair skew ${ }^{[10]}$ | Skew between the earliest and the latest output transitions within the same bank. | - | 50 | 100 | ps |
| $\mathrm{t}_{\text {SKEWO}}$ | Output-output skew ${ }^{[10]}$ | Skew between the earliest and the latest output transitions among all outputs at $\mathrm{Ot}_{\mathrm{U}}$. | - | 100 | 200 | ps |
| ${ }^{\text {tSKEW1 }}$ |  | Skew between the earliest and the latest output transitions among all outputs for which the same phase delay has been selected. | - | 100 | 200 | ps |
| $\mathrm{t}_{\text {SKEW2 }}$ |  | Skew between the nominal output rising edge to the inverted output falling edge. | - | - | 500 | ps |
| $\mathrm{t}_{\text {SKEW3 }}$ | Output-output skew ${ }^{[10]}$ | Skew between non-inverted outputs running at different frequencies. | - | - | 500 | ps |
| $\mathrm{t}_{\text {SKEW4 }}$ |  | Skew between nominal to inverted outputs running at different frequencies. | - | - | 500 | ps |
| $\mathrm{t}_{\text {SKEW5 }}$ |  | Skew between nominal outputs at different power supply levels. | - | - | 650 | ps |
| $\mathrm{t}_{\text {PART }}$ | Part-part skew | Skew between the outputs of any two devices under identical settings and conditions ( $\mathrm{V}_{\mathrm{DDQ}}, \mathrm{V}_{\mathrm{DD}}$,temp, air flow, frequency, etc.). | - | - | 750 | ps |
| tPD0 | Ref-FB propagation delay ${ }^{[11]}$ |  | -250 | - | +250 | ps |
| todcv | Output duty cycle | Fout < 100 MHz , measured at $\mathrm{V}_{\mathrm{DD}} / 2$ | 48 | 49.5/50.5 | 52 | \% |
|  |  | Fout > 100 MHz , measured at $\mathrm{V}_{\mathrm{DD}} / 2$ | 45 | 48/52 | 55 |  |
| $\mathrm{t}_{\text {PWH }}$ | Output high time deviation from 50\% | Measured at 2.0 V for $\mathrm{V}_{\mathrm{DD}}=3.3 \mathrm{~V}$ and at 1.7 V for $\mathrm{V}_{\mathrm{DD}}=2.5 \mathrm{~V}$. | - | - | 1.5 | ns |

## Notes

10. Test load $=20 \mathrm{pF}$, terminated to $\mathrm{V}_{\mathrm{CC}} / 2$. All outputs are equally loaded.
11. $\mathrm{t}_{P D}$ is measured at 1.5 V for $\mathrm{V}_{D D}=3.3 \mathrm{~V}$ and at 1.25 V for $\mathrm{V}_{D D}=2.5 \mathrm{~V}$ with REF rise/fall times of 0.5 ns between $0.8 \mathrm{~V}-2.0 \mathrm{~V}$

## Switching Characteristics

| Parameter | Description | Condition | Min | Typ | Max | Unit |
| :--- | :--- | :--- | :---: | :---: | :---: | :---: |
| $\mathrm{t}_{\mathrm{PWL}}$ | Output low time <br> deviation from $50 \%$ | Measured at 0.8 V for $\mathrm{V}_{\mathrm{DD}}=3.3 \mathrm{~V}$ and at 0.7 V for <br> $\mathrm{V}_{\mathrm{DD}}=2.5 \mathrm{~V}$. | - | - | 2.0 | ns |
| $\mathrm{t}_{\mathrm{R}} / \mathrm{t}_{\mathrm{F}}$ | Output rise/fall time | Measured at $0.8 \mathrm{~V}-2.0 \mathrm{~V}$ for $\mathrm{V}_{\mathrm{DD}}=3.3 \mathrm{~V}$ and <br> $0.7 \mathrm{~V}-1.7 \mathrm{~V}$ for $\mathrm{V}_{\mathrm{DD}}=2.5 \mathrm{~V}$. | 0.15 | - | 1.5 | ns |
| $\mathrm{t}_{\mathrm{LOCK}}$ | PLL lock time ${ }^{[12,13]}$ |  | - | - | 0.5 | ms |
| $\mathrm{t}_{\mathrm{CCJ}}$ | Cycle-cycle jitter | Divide by one output frequency, $\mathrm{FS}=\mathrm{L}, \mathrm{FB}=$ divide by <br> $1,2,4$. | - | 50 | 100 | ps |
|  | Divide by one output frequency, $\mathrm{FS}=\mathrm{M} / \mathrm{H}, \mathrm{FB}=$ divide <br> by $1,2,4$. | - | 70 | 150 | ps |  |

## AC Timing Definitions

Figure 5. Timing Definitions


## Notes

12. $\mathrm{t}_{\text {LOCK }}$ is the time that is required before outputs synchronize to REF. This specification is valid with stable power supplies which are within normal operating limits. 13. Lock detector circuit may be unreliable for input frequencies lower than 4 MHz , or for input signals which contain significant jitter.

## Ordering Information

| Part Number | Package Type | Product Flow |
| :---: | :---: | :---: |
| Pb-free |  |  |
| RoboClock ${ }^{(8)}$ CY7B9950AXC | 32 TQFP | Commercial, $0^{\circ}$ to $70^{\circ} \mathrm{C}$ |
| RoboClock ${ }^{\circledR}$ CY7B9950AXCT | 32 TQFP - Tape and Reel | Commercial, $0^{\circ}$ to $70^{\circ} \mathrm{C}$ |
| RoboClock ${ }^{\circledR}$ CY7B9950AXI | 32 TQFP | Industrial, $-40^{\circ} \mathrm{C}$ to $85^{\circ} \mathrm{C}$ |
| RoboClock ${ }^{\circledR}$ CY7B9950AXIT | 32 TQFP - Tape and Reel | Industrial, $-40^{\circ} \mathrm{C}$ to $85^{\circ} \mathrm{C}$ |

## Ordering Code Definitions



## Package Drawing

Figure 6. 32-Pin Thin Plastic Quad Flatpack $7 \times 7 \times 1.0 \mathrm{~mm}$


## Acronyms

Table 10. Acronyms Used in this Document

| Acronym | Description |
| :--- | :--- |
| CLKOUT | Clock output |
| CMOS | Complementary metal oxide semiconductor |
| DPM | Die pick map |
| EPROM | Erasable programmable read only memory |
| NTSC | National television system committee |
| OE | Output enable |
| PAL | Phase alternate line |
| PD | Power down |
| PLL | Phase locked loop |
| PPM | Parts per million |
| TTL | Transistor transistor logic |

## Document Conventions

## Units of Measure

Table 11. Units of Measure

| Symbol | Unit of Measure | Symbol |  |
| :--- | :--- | :--- | :--- |
| ${ }^{\circ} \mathrm{C}$ | degrees Celsius | $\mu \mathrm{W}$ | microwatts |
| dB | decibels | mA | milliamperes |
| fC | femtoCoulomb | mm | millimeters |
| fF | femtofarads | ms | milliseconds |
| Hz | hertz | mV | millivolts |
| KB | 1024 bytes | nA | nanoamperes |
| Kbit | 1024 bits | ns | nanoseconds |
| kHz | kilohertz | nV | nanovolts |
| $\mathrm{k} \Omega$ | kilohms | $\Omega$ | ohms |
| MHz | megahertz | pA | picoamperes |
| $\mathrm{M} \Omega$ | megaohms | pF | picofarads |
| $\mu \mathrm{A}$ | microamperes | pp | peak-to-peak |
| $\mu \mathrm{F}$ | microfarads | ppm | parts per million |
| $\mu \mathrm{H}$ | microhenrys | ps | picoseconds |
| $\mu \mathrm{s}$ | microseconds | sps | samples per second |
| $\mu \mathrm{V}$ | microvolts | $\sigma$ | sigma: one standard deviation |
| $\mu \mathrm{Vrms}$ | microvolts root-mean-square |  |  |

## Document History Page

| Document Title: RoboClock ${ }^{\circledR}$ CY7B9950 2.5 / 3.3 V, 200 MHz High Speed Multi-Phase PLL Clock Buffer Document Number: 38-07338 |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: |
| Rev. | ECN No. | Submission Date | Orig. of Change | Description of Change |
| ** | 121663 | 11/25/02 | RGL | New Data Sheet |
| *A | 122548 | 12/12/02 | RGL | Removed the PD\#/DIV and DS[1:0] pins in $\mathrm{V}_{\mathrm{IHH}}, \mathrm{V}_{\mathrm{IMM}}$ and $\mathrm{V}_{\mathrm{ILL}}$ for both 2.5 V and 3.3V DC Electrical Specs tables |
| *B | 124646 | 03/05/03 | RGL | Corrected the description of Pin 27(TEST) in the Pin Description table Corrected the description of Pin $12\left(\mathrm{~V}_{\mathrm{DDQ}}\right)$ in the Pin Description table Corrected the Min and Max values of $\mathrm{V}_{\mathrm{DD}}$ from 2.25/2.75 to 2.375/2.625 Volts in the Absolute Maximum Conditions table |
| *C | 433662 | See ECN | RGL | Added Lead-free devices Added Jitter typical values |
| *D | 1562063 | See ECN | PYG/AESA | Added Pb-free CY7B9940V-5AXC to Ordering Information Added Status column to Ordering Information table |
| *E | 2894960 | 03/17/10 | KVM | Fixed typo in output skew settings <br> Changed $\mathrm{V}_{\mathrm{DD}}$ value in Absolute Maximum table <br> Added Operating Conditions table <br> Updated ordering information table <br> Updated package diagram and sales links |
| *F | 3058099 | 10/14/10 | BASH | Added Ordering Code Definitions, Acronyms and Units of Measure Updated template. |

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